

Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/019,052	NEW ET AL.
Examiner	Art Unit	
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SEARCHED

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
506	18	11/20/2007	MS
506	13	11/20/2007	MS
506	15	11/20/2007	MS
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